

Features

- TSOP I package configurable as 1 M × 16 or 2 M × 8 SRAM
- Very high speed: 45 ns
- Temperature ranges
 - Industrial: -40 °C to +85 °C
 - Automotive-A: -40 °C to +85 °C
- Wide voltage range: 2.20 V to 3.60 V
- Ultra-low standby power
 - Typical standby current: 1.5 μA
 - Maximum standby current: 12 μA
- Ultra-low active power
 - Typical active current: 2.2 mA at f = 1 MHz
- Easy memory expansion with \overline{CE}_1 , CE_2 , and \overline{OE} Features
- Automatic power-down when deselected
- CMOS for optimum speed and power
- Offered in Pb-free 48-ball VFBGA and 48-pin TSOP I packages

Functional Description

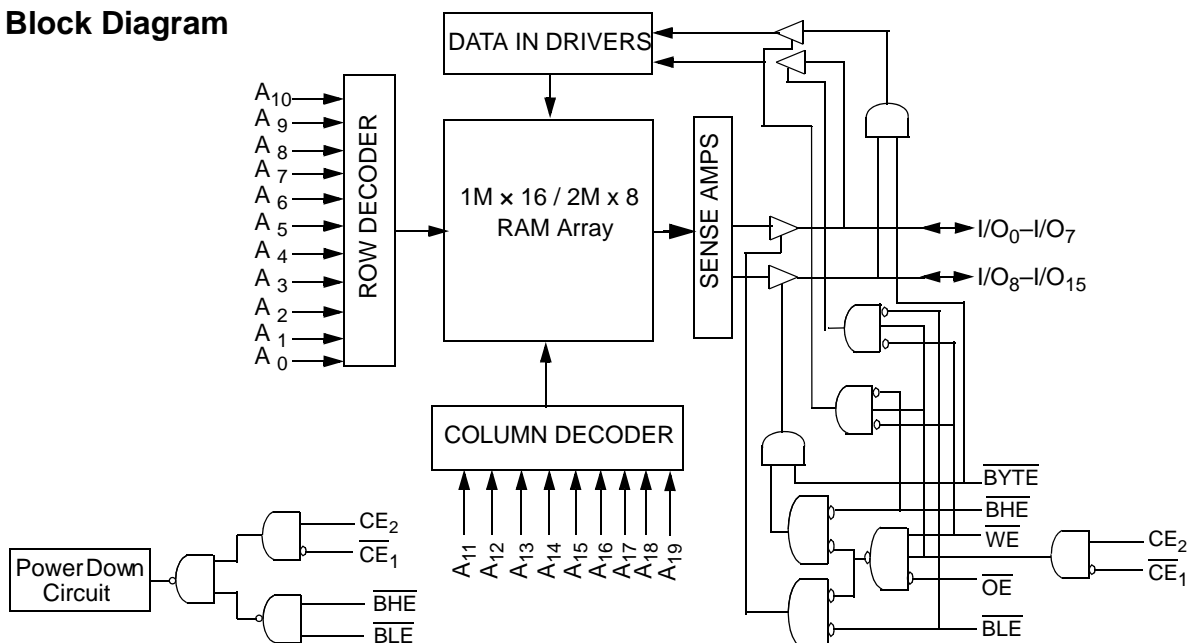
The CY62167EV30 is a high performance CMOS static RAM organized as 1M words by 16 bits or 2M words by 8 bits. This

device features an advanced circuit design that provides an ultra low active current. Ultra low active current is ideal for providing More Battery Life™ (MoBL®) in portable applications such as cellular telephones. The device also has an automatic power down feature that reduces power consumption by 99 percent when addresses are not toggling. Place the device into standby mode when deselected (\overline{CE}_1 HIGH or CE_2 LOW or both \overline{BHE} and \overline{BLE} are HIGH). The input and output pins (I/O₀ through I/O₁₅) are placed in a high impedance state when: the device is deselected (\overline{CE}_1 HIGH or CE_2 LOW), outputs are disabled (\overline{OE} HIGH), both Byte High Enable and Byte Low Enable are disabled (\overline{BHE} , \overline{BLE} HIGH), or a write operation is in progress (CE_1 LOW, CE_2 HIGH and \overline{WE} LOW).

To write to the device, take Chip Enables (\overline{CE}_1 LOW and CE_2 HIGH) and Write Enable (\overline{WE}) input LOW. If Byte Low Enable (\overline{BLE}) is LOW, then data from I/O pins (I/O₀ through I/O₇) is written into the location specified on the address pins (A₀ through A₁₉). If Byte High Enable (\overline{BHE}) is LOW, then data from the I/O pins (I/O₈ through I/O₁₅) is written into the location specified on the address pins (A₀ through A₁₉).

To read from the device, take Chip Enables (\overline{CE}_1 LOW and CE_2 HIGH) and Output Enable (\overline{OE}) LOW while forcing the Write Enable (\overline{WE}) HIGH. If Byte Low Enable (\overline{BLE}) is LOW, then data from the memory location specified by the address pins appears on I/O₀ to I/O₇. If Byte High Enable (\overline{BHE}) is LOW, then data from memory appears on I/O₈ to I/O₁₅. See Truth Table on page 12 for a complete description of read and write modes.

Logic Block Diagram



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Pin Configuration

Figure 1. 48-ball VFBGA (6 × 8 × 1mm) Top View [1, 2]

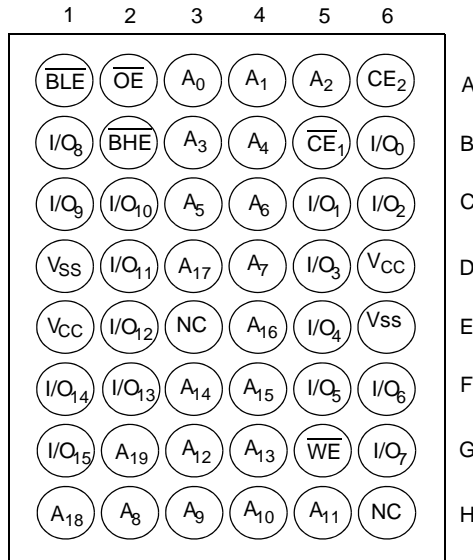
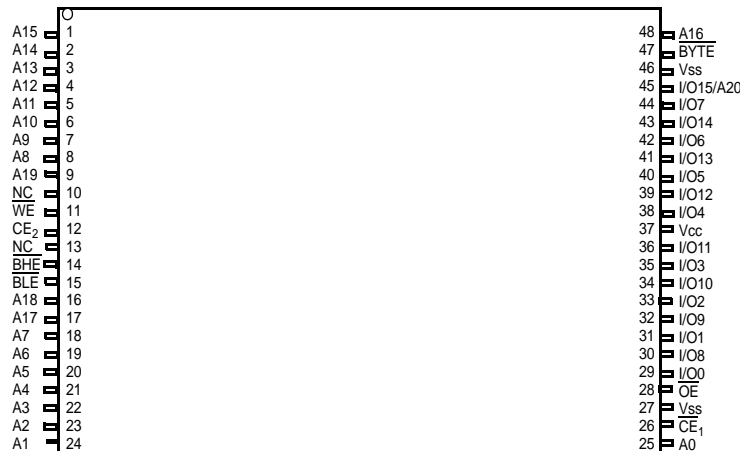


Figure 2. 48-pin TSOP I (12 × 18.4 × 1.0 mm) Top View [2, 3]



Product Portfolio

Product	Range	V _{CC} Range (V)			Speed (ns)	Power Dissipation					
						Operating I _{CC} (mA)				Standby I _{SB2} (μA)	
		f = 1 MHz		f = f _{max}							
		Min	Typ ^[4]	Max		Typ ^[4]	Max	Typ ^[4]	Max	Typ ^[4]	Max
CY62167EV30LL	Industrial / Automotive-A	2.2	3.0	3.6	45	2.2	4.0	25	30	1.5	12

Notes

- Ball H6 for the VFBGA package can be used to upgrade to a 32M density.
- NC pins are not connected on the die.
- The BYTE pin in the 48-pin TSOP I package has to be tied to V_{CC} to use the device as a 1 M × 16 SRAM. The 48-pin TSOP I package can also be used as a 2 M × 8 SRAM by tying the BYTE signal to V_{SS}. In the 2 M × 8 configuration, Pin 45 is A20, while BHE, BLE and I/O₈ to I/O₁₄ pins are not used.
- Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = V_{CC(typ)}, T_A = 25 °C.

Maximum Ratings

Exceeding maximum ratings may shorten the useful life of the device. User guidelines are not tested.

Storage temperature	-65 °C to + 150 °C
Ambient temperature with power applied	-55 °C to + 125 °C
Supply voltage to ground potential	-0.3 V to 3.9 V ($V_{CC(max)}$ + 0.3 V)
DC voltage applied to outputs in High Z state ^[5, 6]	-0.3 V to 3.9 V ($V_{CC(max)}$ + 0.3 V)

DC input voltage ^[5, 6]	-0.3 V to 3.9 V ($V_{CC(max)}$ + 0.3 V)
Output current into outputs (LOW)	20 mA
Static discharge voltage (MIL-STD-883, Method 3015)	>2001 V
Latch-up current	>200 mA

Operating Range

Device	Range	Ambient Temperature	V_{CC} ^[7]
CY62167EV30LL	Industrial / Automotive-A	-40 °C to +85 °C	2.2 V to 3.6 V

Electrical Characteristics

Over the Operating Range

Parameter	Description	Test Conditions	45 ns (Industrial/Automotive-A)			Unit	
			Min	Typ ^[8]	Max		
V_{OH}	Output HIGH voltage	$2.2 \leq V_{CC} \leq 2.7$ $I_{OH} = -0.1$ mA	2.0	-	-	V	
		$2.7 \leq V_{CC} \leq 3.6$ $I_{OH} = -1.0$ mA	2.4	-	-	V	
V_{OL}	Output LOW voltage	$2.2 \leq V_{CC} \leq 2.7$ $I_{OL} = 0.1$ mA	-	-	0.4	V	
		$2.7 \leq V_{CC} \leq 3.6$ $I_{OL} = 2.1$ mA	-	-	0.4	V	
V_{IH}	Input HIGH voltage	$2.2 \leq V_{CC} \leq 2.7$	1.8	-	$V_{CC} + 0.3$ V	V	
		$2.7 \leq V_{CC} \leq 3.6$	2.2	-	$V_{CC} + 0.3$ V	V	
V_{IL}	Input LOW voltage	$2.2 \leq V_{CC} \leq 2.7$	-0.3	-	0.6	V	
		$2.7 \leq V_{CC} \leq 3.6$	For VFBGA package	-0.3	-	0.8	V
			For TSOP I package	-0.3	-	0.7 ^[9]	V
I_{IX}	Input leakage current	$GND \leq V_I \leq V_{CC}$	-1	-	+1	μ A	
I_{OZ}	Output leakage current	$GND \leq V_O \leq V_{CC}$, Output disabled	-1	-	+1	μ A	
I_{CC}	V_{CC} operating supply current	$f = f_{max} = 1/t_{RC}$ $V_{CC} = V_{CC(max)}$	-	25	30	mA	
		$f = 1$ MHz $I_{OUT} = 0$ mA CMOS levels	-	2.2	4.0	mA	
I_{SB1} ^[10]	Automatic power down current—CMOS inputs	$CE_1 \geq V_{CC} - 0.2$ V or $CE_2 \leq 0.2$ V or (BHE and BLE) $\geq V_{CC} - 0.2$ V, $V_{IN} \geq V_{CC} - 0.2$ V, $V_{IN} \leq 0.2$ V, $f = f_{max}$ (address and data only), $f = 0$ (OE, and WE), $V_{CC} = V_{CC(max)}$	-	1.5	12	μ A	
I_{SB2} ^[10]	Automatic power down current—CMOS inputs	$CE1 \geq V_{CC} - 0.2$ V or $CE2 \leq 0.2$ V or (BHE and BLE) $\geq V_{CC} - 0.2$ V, $V_{IN} \geq V_{CC} - 0.2$ V or $V_{IN} \leq 0.2$ V, $f = 0$, $V_{CC} = V_{CC(max)}$	-	1.5	12	μ A	

Notes

- $V_{IL(min)}$ = -2.0 V for pulse durations less than 20 ns.
- $V_{IH(max)}$ = $V_{CC} + 0.75$ V for pulse durations less than 20 ns.
- Full Device AC operation assumes a 100 μ s ramp time from 0 to $V_{CC(min)}$ and 200 μ s wait time after V_{CC} stabilization.
- Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at $V_{CC} = V_{CC(typ)}$, $T_A = 25$ °C.
- Under DC conditions the device meets a V_{IL} of 0.8 V. However, in dynamic conditions Input LOW Voltage applied to the device must not be higher than 0.7 V. This is applicable to TSOP I package only.
- Chip enables (\overline{CE}_1 and \overline{CE}_2), byte enables (\overline{BHE} and \overline{BLE}) and \overline{BYTE} must be tied to CMOS levels to meet the $I_{SB1}/I_{SB2} / I_{CCDR}$ spec. Other inputs can be left floating.

Capacitance

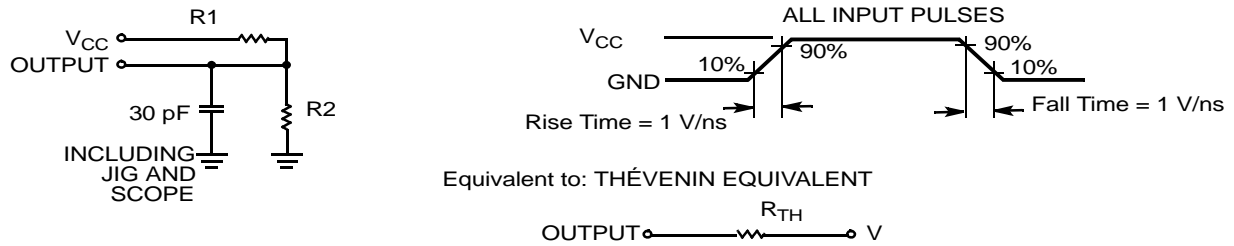
Parameter ^[11]	Description	Test Conditions	Max	Unit
C _{IN}	Input capacitance	T _A = 25 °C, f = 1 MHz, V _{CC} = V _{CC(typ)}	10	pF
C _{OUT}	Output capacitance		10	pF

Thermal Resistance

Parameter ^[11]	Description	Test Conditions	48-ball VFBGA (6 x 8 x 1mm)	48-pin TSOP I	Unit
Θ _{JA}	Thermal resistance (Junction to ambient)	Still air, soldered on a 3 x 4.5 inch, two-layer printed circuit board	55	60	°C/W
Θ _{JC}	Thermal resistance (Junction to case)		16	4.3	°C/W

AC Test Loads and Waveforms

Figure 3. AC Test Loads and Waveforms



Parameters	2.2 V to 2.7 V	2.7 V to 3.6 V	Unit
R1	16667	1103	Ω
R2	15385	1554	Ω
R _{TH}	8000	645	Ω
V _{TH}	1.20	1.75	V

Note

11. Tested initially and after any design or process changes that may affect these parameters.

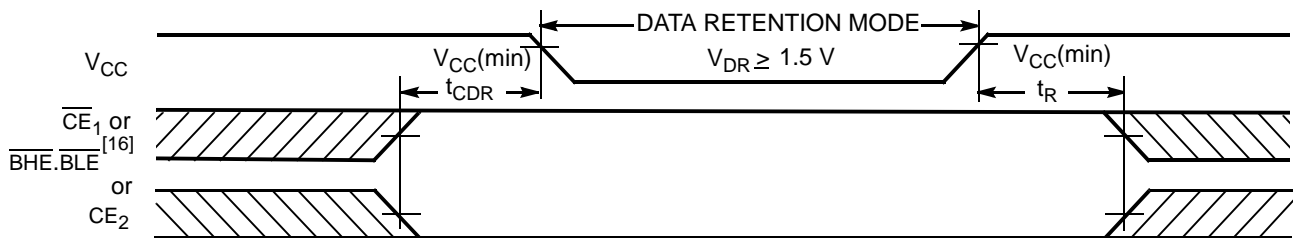
Data Retention Characteristics

Over the Operating Range

Parameter	Description	Conditions		Min	Typ ^[12]	Max	Unit	
V _{DR}	V _{CC} for data retention			1.5	–	–	V	
I _{CCDR} ^[13]	Data retention current	V _{CC} = 1.5 V to 3.0 V, CE ₁ ≥ V _{CC} – 0.2 V or CE ₂ ≤ 0.2 V or (BHE and BLE) ≥ V _{CC} – 0.2 V, V _{IN} ≥ V _{CC} – 0.2 V or V _{IN} ≤ 0.2 V	Industrial	48-pin TSOP I	–	–	8	μA
		V _{CC} = 1.5 V, CE ₁ ≥ V _{CC} – 0.2 V or CE ₂ ≤ 0.2 V or (BHE and BLE) ≥ V _{CC} – 0.2 V, V _{IN} ≥ V _{CC} – 0.2 V or V _{IN} ≤ 0.2 V	Industrial	Other packages	–	–	10	μA
			Automotive-A	All packages	–	–	10	μA
t _{CDR} ^[14]	Chip deselect to data retention time			0	–	–	–	
t _R ^[15]	Operation recovery time			45	–	–	ns	

Data Retention Waveform

Figure 4. Data Retention Waveform



Notes

- 12. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = V_{CC(typ)}, T_A = 25 °C.
- 13. Chip enables (CE₁ and CE₂), byte enables (BHE and BLE) and BYTE must be tied to CMOS levels to meet the I_{SB1} / I_{SB2} / I_{CCDR} spec. Other inputs can be left floating.
- 14. Tested initially and after any design or process changes that may affect these parameters.
- 15. Full device operation requires linear V_{CC} ramp from V_{DR} to V_{CC(min)} ≥ 100 μs or stable at V_{CC(min)} ≥ 100 μs.
- 16. BHE.BLE is the AND of both BHE and BLE. Deselect the chip by either disabling the chip enable signals or by disabling both BHE and BLE.

Switching Characteristics

Parameter [17, 18]	Description	45 ns (Industrial / Automotive-A)		Unit
		Min	Max	
READ CYCLE				
t_{RC}	Read cycle time	45	–	ns
t_{AA}	Address to data valid	–	45	ns
t_{OHA}	Data hold from address change	10	–	ns
t_{ACE}	\overline{CE}_1 LOW and CE_2 HIGH to data valid	–	45	ns
t_{DOE}	\overline{OE} LOW to data valid	–	22	ns
t_{LZOE}	\overline{OE} LOW to Low Z [19]	5	–	ns
t_{HZOE}	\overline{OE} HIGH to High Z [19, 20]	–	18	ns
t_{LZCE}	\overline{CE}_1 LOW and CE_2 HIGH to Low Z [19]	10	–	ns
t_{HZCE}	\overline{CE}_1 HIGH and CE_2 LOW to High Z [19, 20]	–	18	ns
t_{PU}	\overline{CE}_1 LOW and CE_2 HIGH to power-up	0	–	ns
t_{PD}	\overline{CE}_1 HIGH and CE_2 LOW to power-down	–	45	ns
t_{DBE}	BLE / BHE LOW to data valid	–	45	ns
t_{LZBE}	\overline{BLE} / \overline{BHE} LOW to Low Z [19]	10	–	ns
t_{HZBE}	\overline{BLE} / \overline{BHE} HIGH to High Z [19, 20]	–	18	ns
WRITE CYCLE^[21]				
t_{WC}	Write cycle time	45	–	ns
t_{SCE}	\overline{CE}_1 LOW and CE_2 HIGH to write end	35	–	ns
t_{AW}	Address setup to write end	35	–	ns
t_{HA}	Address hold from write end	0	–	ns
t_{SA}	Address setup to write start	0	–	ns
t_{PWE}	\overline{WE} pulse width	35	–	ns
t_{BW}	\overline{BLE} / \overline{BHE} LOW to write end	35	–	ns
t_{SD}	Data setup to write end	25	–	ns
t_{HD}	Data hold from write end	0	–	ns
t_{HZWE}	\overline{WE} LOW to High Z [19, 20]	–	18	ns
t_{LZWE}	\overline{WE} HIGH to Low Z [19]	10	–	ns

Notes

17. Test conditions for all parameters other than tri-state parameters assume signal transition time of 1 V/ns, timing reference levels of $V_{CC(typ)}/2$, input pulse levels of 0 to $V_{CC(typ)}$, and output loading of the specified I_{OL}/I_{OH} as shown in [Figure 3 on page 5](#).
18. AC timing parameters are subject to byte enable signals (\overline{BHE} or \overline{BLE}) not switching when chip is disabled. See [application note AN13842](#) for further clarification.
19. At any temperature and voltage condition, t_{HZCE} is less than t_{LZCE} , t_{HZBE} is less than t_{LZBE} , t_{HZOE} is less than t_{LZOE} , and t_{HZWE} is less than t_{LZWE} for any device.
20. t_{HZOE} , t_{HZCE} , t_{HZBE} , and t_{HZWE} transitions are measured when the outputs enter a high impedance state.
21. The internal write time of the memory is defined by the overlap of \overline{WE} , $\overline{CE}_1 = V_{IL}$, \overline{BHE} or \overline{BLE} or both = V_{IL} , and $CE_2 = V_{IH}$. All signals must be ACTIVE to initiate a write and any of these signals can terminate a write by going INACTIVE. The data input setup and hold timing must refer to the edge of the signal that terminates the write.

Switching Waveforms

Figure 5. Read Cycle No. 1 (Address Transition Controlled) [22, 23]

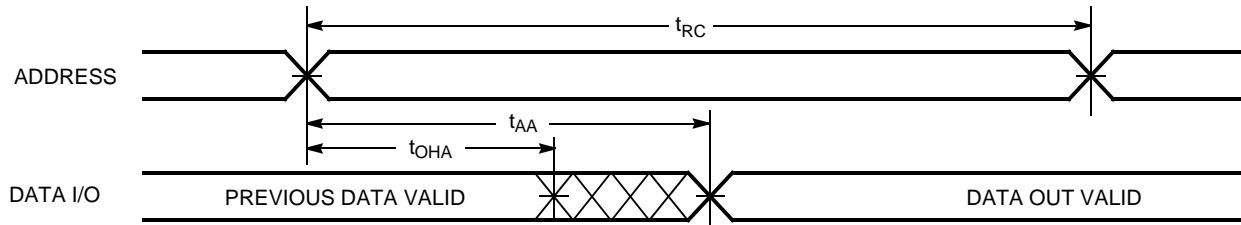
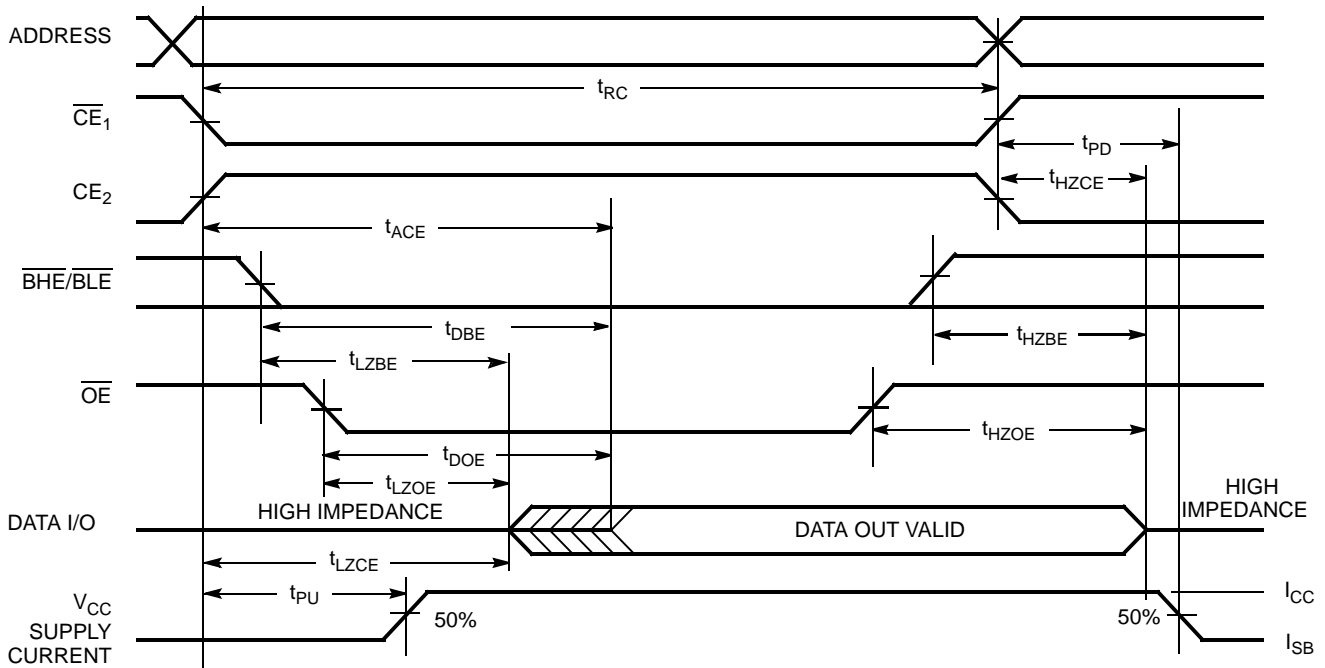


Figure 6. Read Cycle No. 2 (\overline{OE} Controlled) [23, 24]

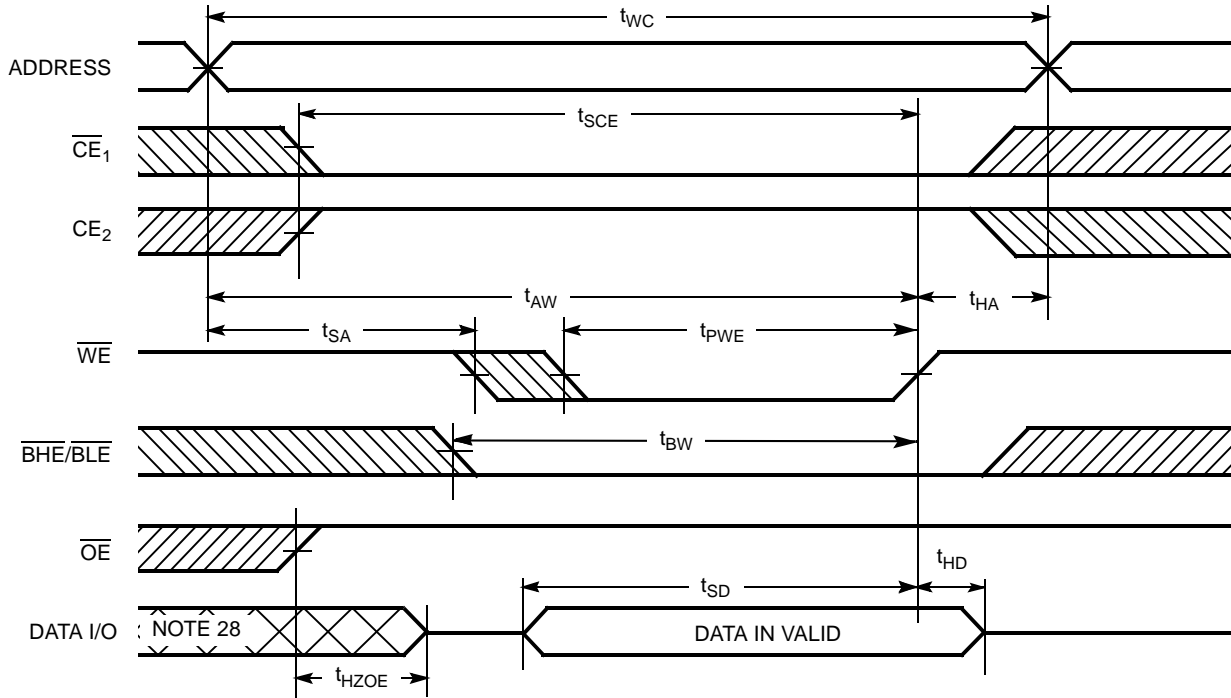


Notes

- 22. The device is continuously selected. \overline{OE} , $\overline{CE}_1 = V_{IL}$, \overline{BHE} , \overline{BLE} or both = V_{IL} , and $CE_2 = V_{IH}$.
- 23. \overline{WE} is HIGH for read cycle.
- 24. Address valid before or similar to \overline{CE}_1 , \overline{BHE} , \overline{BLE} transition LOW and CE_2 transition HIGH.

Switching Waveforms (continued)

Figure 7. Write Cycle No. 1 (\overline{WE} Controlled) [25, 26, 27]

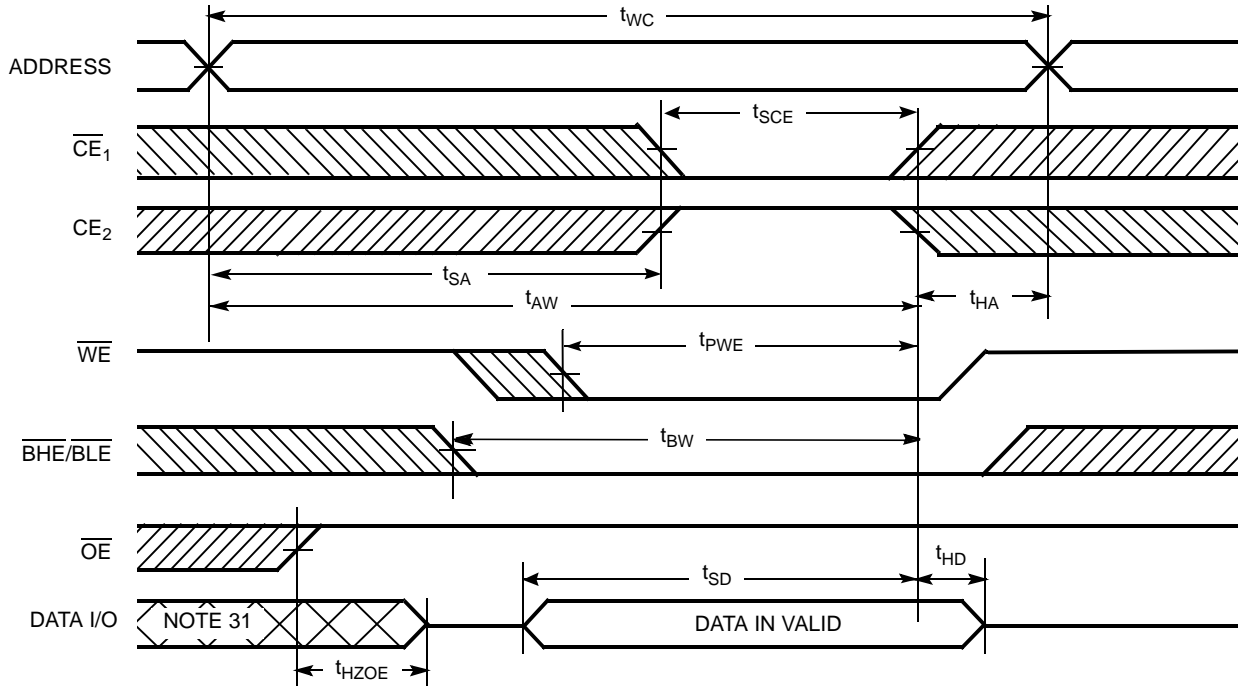


Notes

- 25. The internal write time of the memory is defined by the overlap of \overline{WE} , $\overline{CE}_1 = V_{IL}$, \overline{BHE} or \overline{BLE} or both = V_{IL} , and $CE_2 = V_{IH}$. All signals must be ACTIVE to initiate a write and any of these signals can terminate a write by going INACTIVE. The data input setup and hold timing must refer to the edge of the signal that terminates the write.
- 26. Data I/O is high impedance if $OE = V_{IH}$.
- 27. If \overline{CE}_1 goes HIGH and CE_2 goes LOW simultaneously with $\overline{WE} = V_{IH}$, the output remains in a high impedance state.
- 28. During this period the I/Os are in output state. Do not apply input signals.

Switching Waveforms (continued)

Figure 8. Write Cycle No. 2 (\overline{CE}_1 or CE_2 Controlled) [29, 30]



Notes

- 29. The internal write time of the memory is defined by the overlap of \overline{WE} , $\overline{CE}_1 = V_{IL}$, \overline{BHE} or \overline{BLE} or both = V_{IL} , and $CE_2 = V_{IH}$. All signals must be ACTIVE to initiate a write and any of these signals can terminate a write by going INACTIVE. The data input setup and hold timing must refer to the edge of the signal that terminates the write.
- 30. If \overline{CE}_1 goes HIGH and CE_2 goes LOW simultaneously with $\overline{WE} = V_{IH}$, the output remains in a high impedance state.
- 31. During this period the I/Os are in output state. Do not apply input signals.

Switching Waveforms (continued)

Figure 9. Write Cycle No. 3 (\overline{WE} controlled, \overline{OE} LOW)^[32]

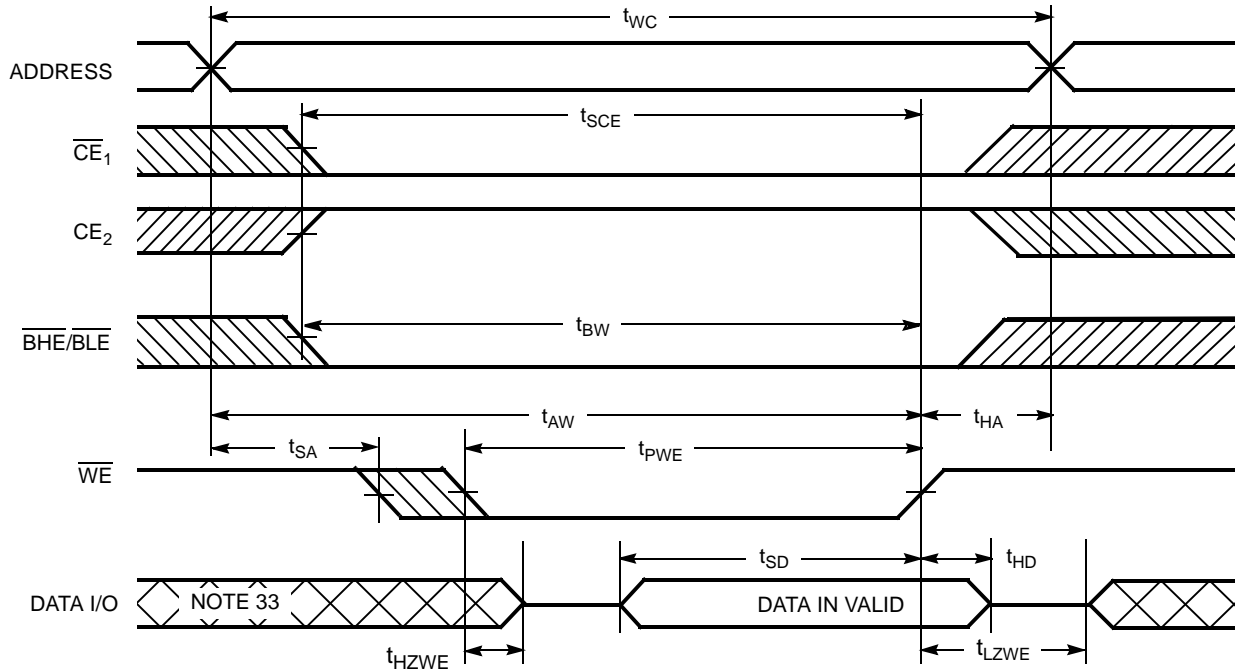
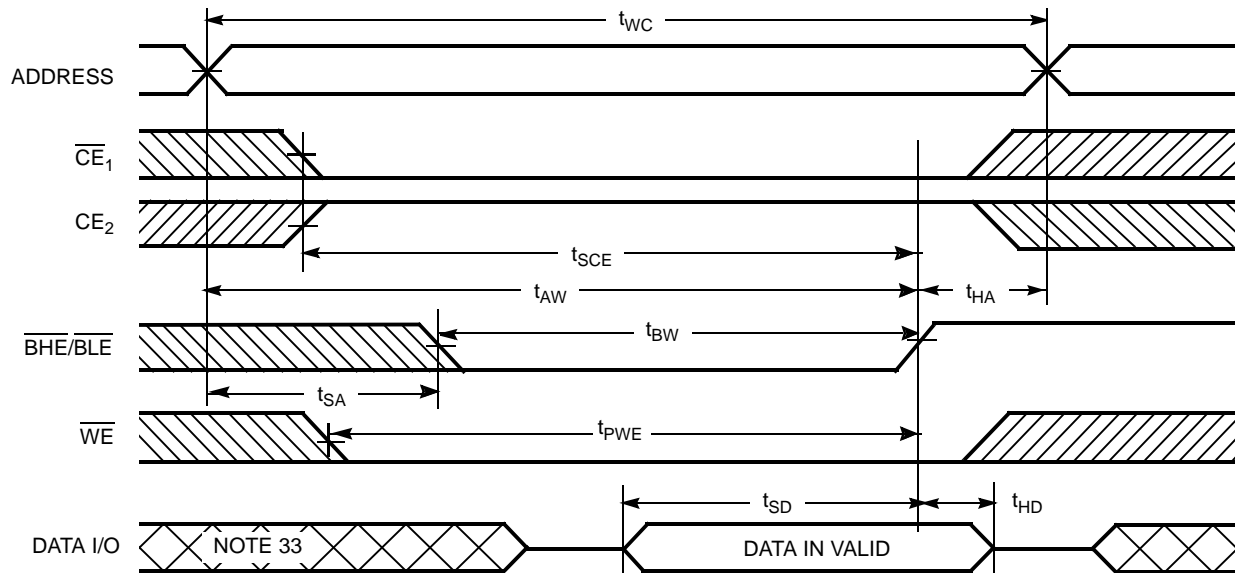


Figure 10. Write Cycle No. 4 ($\overline{BHE}/\overline{BLE}$ controlled, \overline{OE} LOW)^[32]



Notes

- 32. If \overline{CE}_1 goes HIGH and CE_2 goes LOW simultaneously with $\overline{WE} = V_{IH}$, the output remains in a high impedance state.
- 33. During this period the I/Os are in output state. Do not apply input signals.

Truth Table

\overline{CE}_1	CE_2	\overline{WE}	\overline{OE}	\overline{BHE}	\overline{BLE}	Inputs/Outputs	Mode	Power
H	X ^[34]	X	X	X ^[34]	X ^[34]	High Z	Deselect/Power-down	Standby (I_{SB})
X ^[34]	L	X	X	X ^[34]	X ^[34]	High Z	Deselect/Power-down	Standby (I_{SB})
X ^[34]	X ^[34]	X	X	H	H	High Z	Deselect/Power-down	Standby (I_{SB})
L	H	H	L	L	L	Data Out (I/O_0 – I/O_{15})	Read	Active (I_{CC})
L	H	H	L	H	L	Data Out (I/O_0 – I/O_7); High Z (I/O_8 – I/O_{15})	Read	Active (I_{CC})
L	H	H	L	L	H	High Z (I/O_0 – I/O_7); Data Out (I/O_8 – I/O_{15})	Read	Active (I_{CC})
L	H	H	H	L	H	High Z	Output disabled	Active (I_{CC})
L	H	H	H	H	L	High Z	Output disabled	Active (I_{CC})
L	H	H	H	L	L	High Z	Output disabled	Active (I_{CC})
L	H	L	X	L	L	Data In (I/O_0 – I/O_{15})	Write	Active (I_{CC})
L	H	L	X	H	L	Data In (I/O_0 – I/O_7); High Z (I/O_8 – I/O_{15})	Write	Active (I_{CC})
L	H	L	X	L	H	High Z (I/O_0 – I/O_7); Data In (I/O_8 – I/O_{15})	Write	Active (I_{CC})

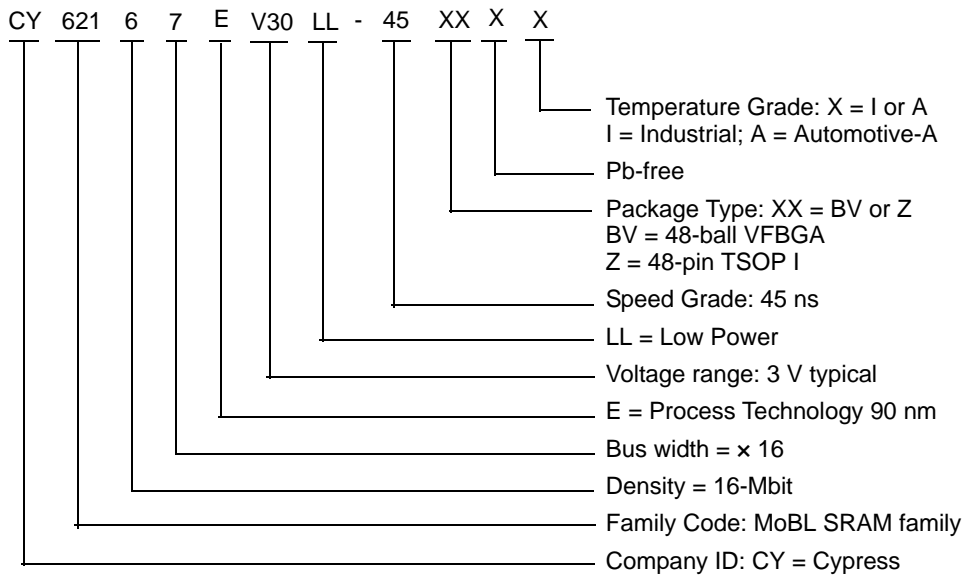
Note

34. The 'X' (Don't care) state for the chip enables and Byte enables in the truth table refer to the logic state (either HIGH or LOW). Intermediate voltage levels on these pins is not permitted.

Ordering Information

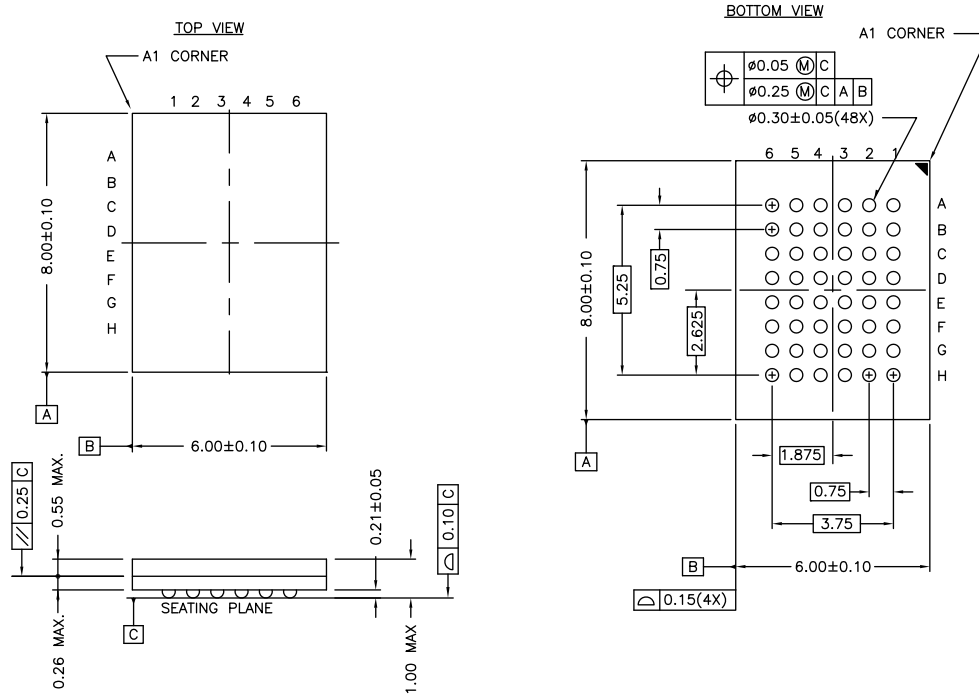
Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
45	CY62167EV30LL-45BVI	51-85150	48-ball VFBGA (6 × 8 × 1 mm), Package Code: BV48	Industrial
	CY62167EV30LL-45BVXI	51-85150	48-ball VFBGA (6 × 8 × 1 mm) (Pb-free), Package Code: BZ48	
	CY62167EV30LL-45ZXI	51-85183	48-pin TSOP I (Pb-free)	
	CY62167EV30LL-45BVXA	51-85150	48-ball VFBGA (6 × 8 × 1 mm) (Pb-free), Package Code: BZ48	Automotive-A
	CY62167EV30LL-45ZXA	51-85183	48-pin TSOP I (Pb-free)	

Ordering Code Definitions



Package Diagrams

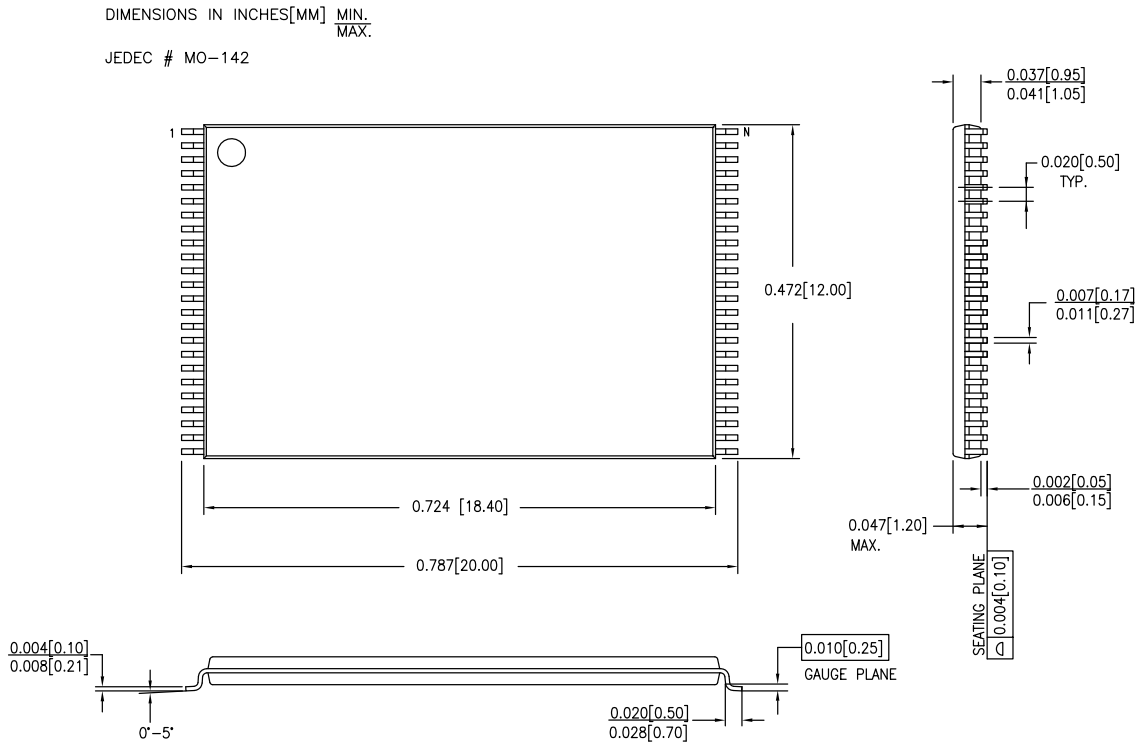
Figure 11. 48-ball VFBGA (6 × 8 × 1.0 mm) BV48 (Non Pb-free) / BZ48 (Pb-free) Package Outline, 51-85150



51-85150 *G

Package Diagrams

Figure 12. 48-pin TSOP I (12 × 18.4 × 1.0 mm) Z48A Package Outline, 51-85183



51-85183 *C

Acronyms

Acronym	Description
BHE	byte high enable
BLE	byte low enable
CE	chip enable
CMOS	complementary metal oxide semiconductor
I/O	input/output
OE	output enable
SRAM	static random access memory
TSOP	thin small outline package
VFBGA	very fine-pitch ball grid array
WE	write enable

Document Conventions

Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
MHz	megahertz
μA	microampere
μs	microsecond
mA	milliampere
mm	millimeter
ns	nanosecond
Ω	ohm
%	percent
pF	picofarad
V	volt
W	watt

Document History Page

Document Title: CY62167EV30 MoBL [®] , 16-Mbit (1 M × 16 / 2 M × 8) Static RAM				
Document Number: 38-05446				
Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change
**	202600	AJU	01/23/2004	New Data Sheet
*A	463674	NXR	See ECN	Converted from Advance Information to Preliminary Removed 'L' bin and 35 ns speed bin from product offering Modified Data sheet to include x8 configurability. Changed ball E3 in FBGA pinout from DNU to NC Changed the I _{SB2(Typ)} value from 1.3 μA to 1.5 μA Changed the I _{CC(Max)} value from 40 mA to 25 mA Changed V _{cc} stabilization time in footnote #9 from 100 μs to 200 μs Changed the AC Test Load Capacitance value from 50 pF to 30 pF Corrected typo in Data Retention Characteristics (t _R) from 100 μs to t _{RC} ns Changed t _{OHA} , t _{LZCE} , t _{LZBE} , and t _{LZWE} from 6 ns to 10 ns Changed t _{LZOE} from 3 ns to 5 ns. Changed t _{HZOE} , t _{HZCE} , t _{HZBE} , and t _{HZWE} from 15 ns to 18 ns Changed t _{SCE} , t _{AW} , and t _{BW} from 40 ns to 35 ns Changed t _{PE} from 30 ns to 35 ns Changed t _{SD} from 20 ns to 25 ns Updated 48-ball FBGA Package Information. Updated the Ordering Information table
*B	469169	NSI	See ECN	Minor Change: Moved to external web
*C	1130323	VKN	See ECN	Converted from preliminary to final Changed I _{CC} max spec from 2.8 mA to 4.0 mA for f = 1MHz Changed I _{CC} typ spec from 22 mA to 25 mA for f = f _{max} Changed I _{CC} max spec from 25 mA to 30 mA for f = f _{max} Added V _{IL} spec for TSOP I package and footnote# 9 Added footnote# 10 related to I _{SB2} and I _{CCDR} Changed I _{SB1} and I _{SB2} spec from 8.5 μA to 12 μA Changed I _{CCDR} spec from 8 μA to 10 μA Added footnote# 15 related to AC timing parameters
*D	1323984	VKN / AESA	See ECN	Modified I _{CCDR} spec for TSOP I package Added 48-ball VFBGA (6 × 7 × 1mm) package Added footnote# 1 related to VFBGA (6 × 7 × 1mm) package Updated Ordering Information table
*E	2678799	VKN / PYRS	03/25/2009	Added Automotive-A information
*F	2720234	VKN / AESA	06/17/2009	Included -45BVXA part in the Ordering information table
*G	2880574	VKN	02/18/2010	Modified I _{CCDR} spec from 8 μA to 10 μA for Auto-A grade. Added Contents . Updated all package diagrams. Updated links in Sales , Solutions , and Legal Information .
*H	2934396	VKN	06/03/10	Added footnote #25 related to chip enable. Updated template.
*I	3006301	RAME	08/12/2010	Included BHE and BLE in I _{SB1} , I _{SB2} , and I _{CCDR} test conditions to reflect Byte power down feature. Removed 48-ball VFBGA (6 × 7 × 1 mm) package related information. Added Acronyms and Ordering code definition. Format updates to match template.

Document History Page (continued)

Document Title: CY62167EV30 MoBL®, 16-Mbit (1 M x 16 / 2 M x 8) Static RAM Document Number: 38-05446				
Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change
*J	3295175	RAME	06/29/2011	Updated Package Diagrams . Added Document Conventions . Removed reference to AN1064 SRAM system guidelines. Added I _{SB1} to footnotes 10 and 13 . Added byte enables to footnote 34 and referenced to Truth table.
*K	3411301	TAVA	10/17/2011	Updated Switching Waveforms . Updated Package Diagrams . Updated in new template.
*L	3667939	TAVA	07/09/2012	Updated Ordering Information (No change in part numbers, updated details in Package Type column only). Updated Package Diagrams (Spec 51-85150 (Updated figure caption only, no change in revision)).

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